

Round Reduction Using Faults

Hamid Choukri, Michael Tunstall

Security Technologies Department

(hamid.choukri - michael.tunstall) @gemplus.com

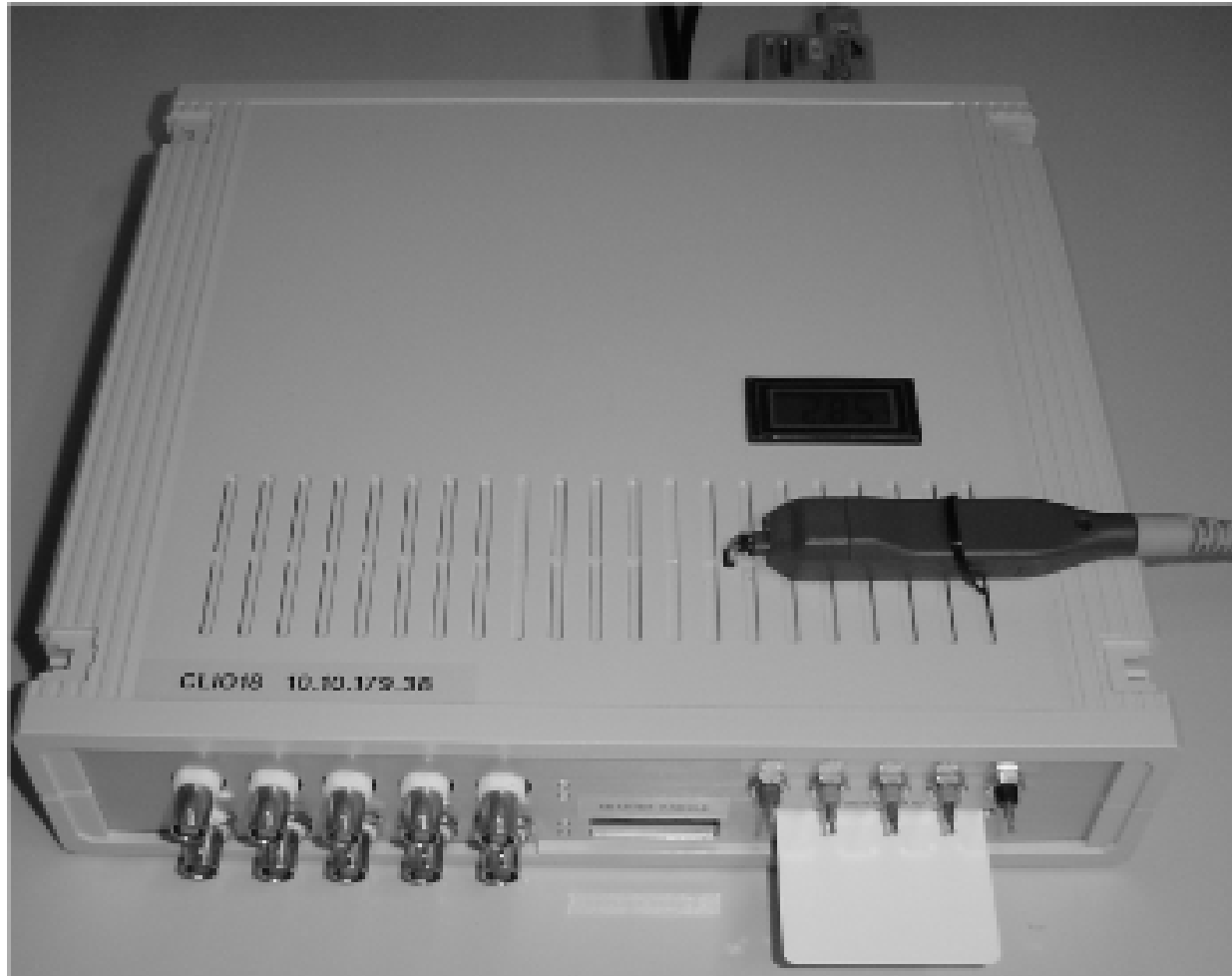
Description

- The objective
 - Break secret keys in very short time.
- The target
 - Secret key algorithms based on a function that is computed iteratively such as the DES (Data Encryption Standard) or the AES (Advanced Encryption Standard).
- The implementation
 - Naïve implementation of AES without counter measures.
- The operating mode
 - A combination of fault attack injection and a cryptanalysis.
 - The fault type is a transient glitch on Vcc (power supply)

Fault configuration

- The chip analysis and tolerance
 - Applied voltage
 - The normal voltage is 5 Volts.
 - The voltage varied from 3 volts to 5 volts.
 - External frequency
 - The normal frequency is 5 MHz
 - The frequency varied from 1 MHz to 5 MHz.
 - Glitch duration.
 - The glitch varied from 1 to 10 clock cycle
- Find optimal configuration for voltage/Frequency/Glitch

Fault Injection Equipment



Fault Target

RoundFunction:

```
call  AddRoundKey
call  ShiftRows
call  SubBytes
call  MixColumns
call  KeySchedule
```

```
movlw  0Ah
movwf  RoundCounter
RoundLabel:
```

```
call  RoundFunction
```

```
decfsz RoundCounter
goto  RoundLabel
```

```
call  AddRoundKey
```

Sensitive Locations

Decrement Task:

```
RoundCounter <= RoundCounter - 1
```

Testing Task:

```
If (RoundCounter == 0)
```

```
Status <= 1
```

```
Else
```

```
Status <= 0
```

Jump Task:

```
If (Status == 1)
```

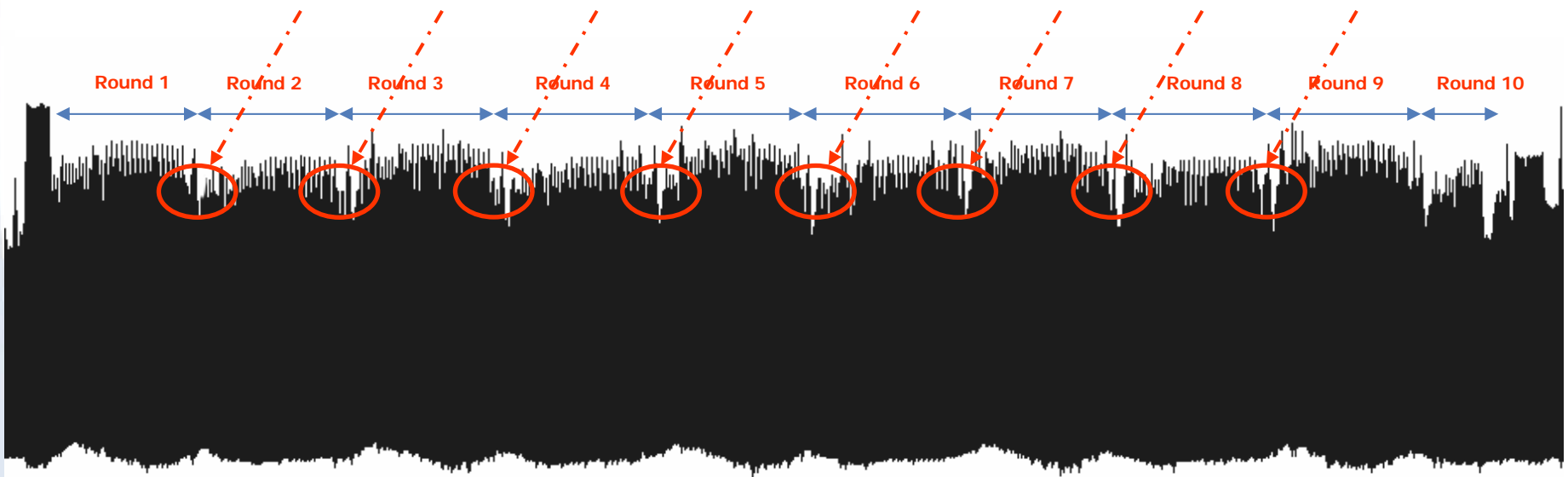
```
PC <= PC1
```

```
Else
```

```
PC <= PC2
```

Processing Localization

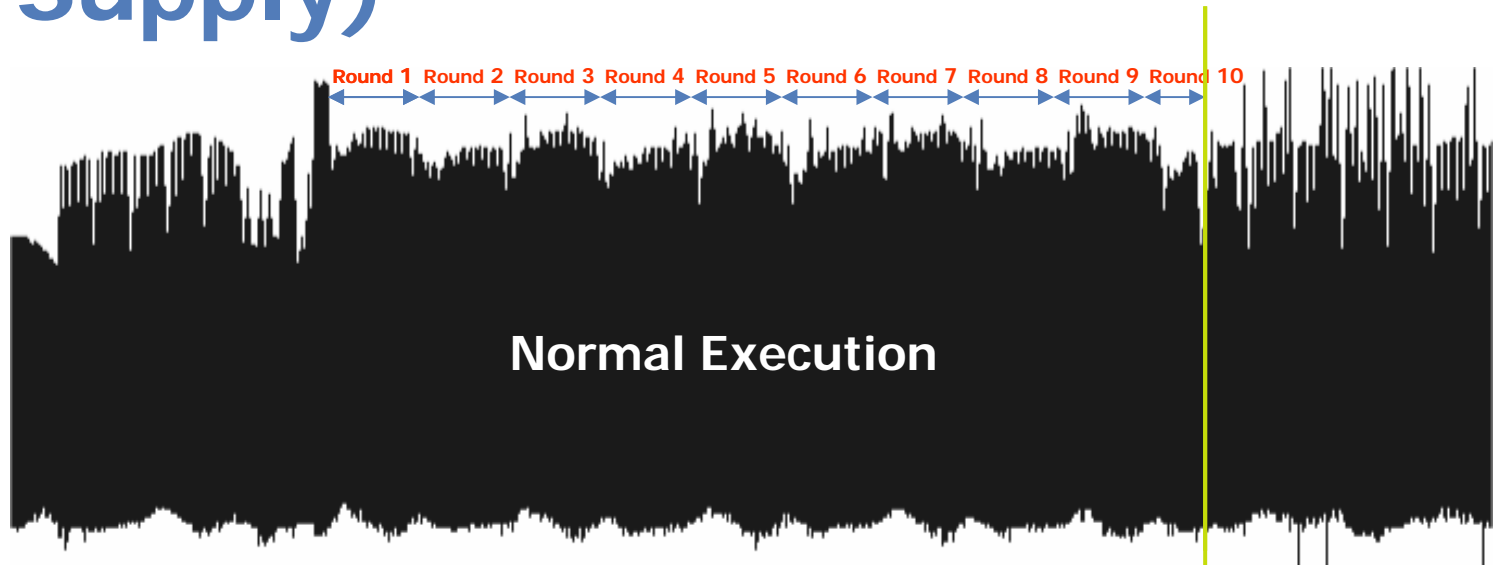
- A naive implementation.
- Rounds are visible in the power consumption.



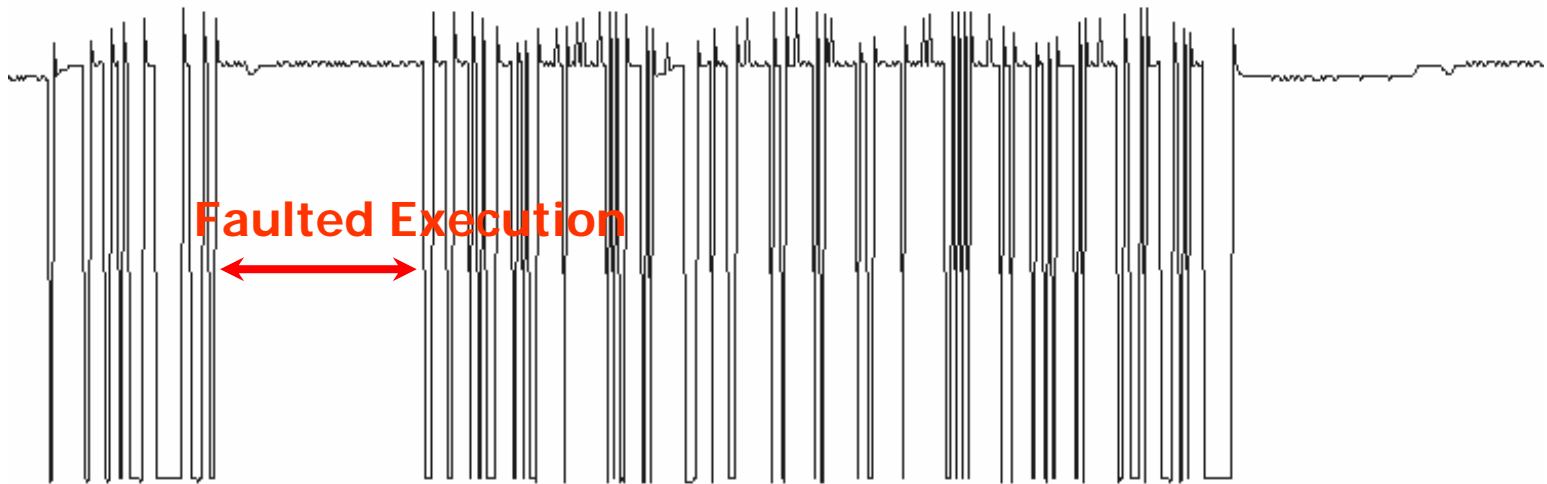
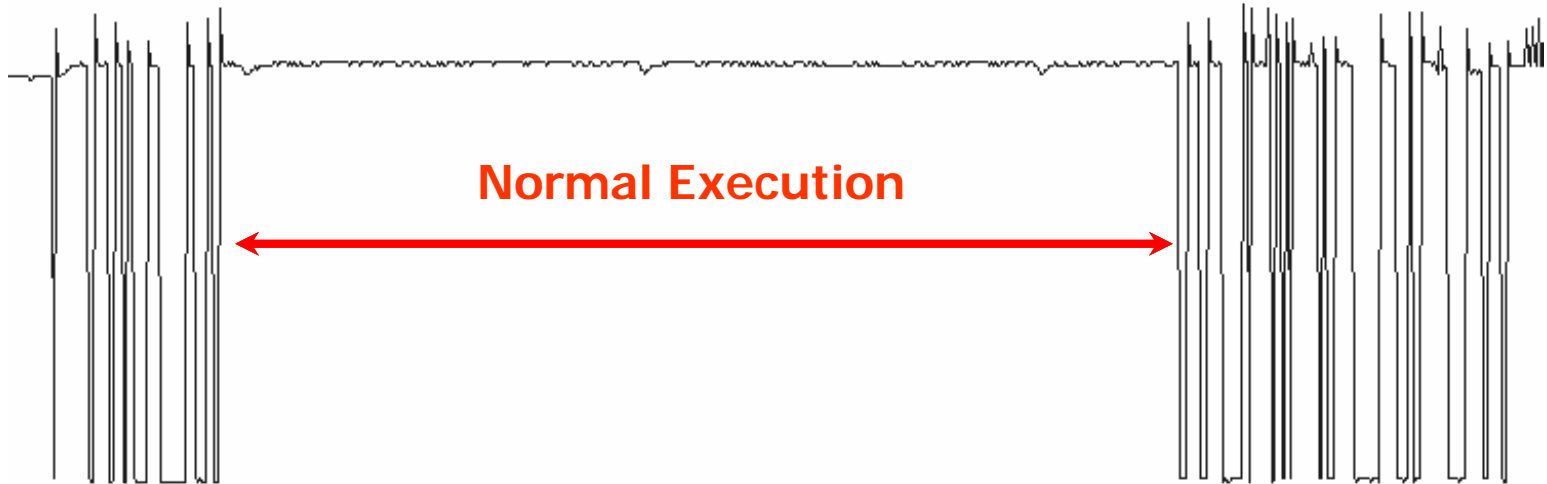
The Fault Target

- A glitch was injected at a number of points where the end of the first round was assumed to be.
- This was done with a card with a known key to be able to detect when a successful fault occurred.
- It is also possible to be done with unknown key, but we will have the check IO time execution and the status returned by the card.

Detecting a Fault (Power Supply)



Detecting a Fault (I/O Com)



Results interpretation

- 2 faulty cipher-texts, will be:

```
AddRoundKey( ) ;  
ShiftRows( ) ;  
SubBytes( ) ;  
MixColumns( ) ;  
AddRoundKey( ) ;
```

```
AddRoundKey( ) ;  
ShiftRows( ) ;  
SubBytes( ) ;  
AddRoundKey( ) ;
```

- Depending on the implementation

Using the Results

- With messages m_1 and m_2 , producing cipher texts c_1 and c_2 .
- Byte-wise exhaustive search for k , in equations:

$$\text{SubBytes}(m_1 \oplus k) \oplus \text{SubBytes}(m_2 \oplus k) = \text{MixColumn}^{-1}(c_1 \oplus c_2)$$

$$\text{SubBytes}(m_1 \oplus k) \oplus \text{SubBytes}(m_2 \oplus k) = (c_1 \oplus c_2)$$

- Each equation will give 2^{16} possible hypothesis for k .
- In our case the equation to use was known.
- A wrong fault location injection with a faulty result could be easily removed from the acquired result ($P=3.14 \times 10^{-3}$).

Other algorithms

- The attack could be applied to other secret key algorithms since the only difference is in the manner in which the result is exploited.
- As example, the DES reduction to one round give a key-space of 2^{24} to be searched from one corrupt ciphertext.

Counter measures

- Redundancy check of RoundCounter.
- Repeat all or part of the algorithm.
- Add Random delay so that it is difficult to find the correct position.
- Microcontroller with glitch sensor.
- ...

Conclusion

- The round reduction is experimentally possible in presence of naïve implementation and without hardware counter measures.
- The attack requires a high degree of control with regard to where the fault take place but relatively little calculation after acquiring the desired corrupt cipher-texts.
- Other fault attacks are possible exploiting the mathematical properties but needs more complex post-treatment.

Thank you

Contacts:

hamid.choukri@gemplus.com

michael.tunstall@gemplus.com or m.j.tunstall@rhul.ac.uk